INTERNATIONAL STANDARD

IEC 60191-6-10

First edition 2003-11

Mechanical standardization of semiconductor devices -

Part 6-10:

General rules for the preparation of outline drawings of surface mounted semiconductor device packages – Dimensions of P-VSON

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Normalisation mécanique des dispositifs à semiconducteurs -

Partie 6-10:

Règles générales pour la préparation des dessins d'encombrement des dispositifs à semiconducteurs pour montage en surface – Dimensions des boîtiers P-VSON



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International Electrotechnical Commission, 3, rue de Varembé, PO Box 131, CH-1211 Geneva 20, Switzerland Telephone: +41 22 919 02 11 Telefax: +41 22 919 03 00 E-mail: inmail@iec.ch Web: www.iec.ch



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES -

Part 6-10: General rules for the preparation of outline drawings of surface mounted semiconductor device packages – Dimensions of P-VSON

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International Standard IEC 60191-6-10 has been prepared by subcommittee 47D: Mechanical standardization of semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47D/551/FDIS	47D565/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until 2005. At this date, the publication will be

- · reconfirmed;
- · withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

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MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES -

Part 6-10: General rules for the preparation of outline drawings of surface mounted semiconductor device packages – Dimensions of P-VSON

1 Scope

This part of IEC 60191 provides the common outline drawings and dimensions for all types of structures and composed materials of plastic very thin small outline non-lead package (hereinafter called P-VSON).

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60191(all parts), Mechanical standardization of semiconductor devices

ISO/DIS 2692: Geometrical Product Specification (GPS) – Geometrical tolerancing – Maximum material requirement (MMR) and least material requirement (LMR).

3 Terms and definitions

For the purposes of this document, the following definition, as well as those given in other parts of the IEC 60191 series, apply.

3.1 P-VSON

plastic very thin-profile small outline, flat package with no leads

NOTE The package leads (terminals) are on opposite sides of the bottom of the package body and do not extend beyond the package body.